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	closure Statement pplicant	Applicant Christian Block et al.	
(Use several sheets if necessary) (37 CFR §1.98(b))		Filing Date March 1, 2005	Group Art Unit 2836

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 14219-0079US1	Application No. 10/526,278	
	closure Statement	Applicant Christian Block et al.		
(Use several sheets if necessary) (37 CFR §1.98(b))		Filing Date March 1, 2005	Group Art Unit 2836	

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